



US00D670402S

(12) **United States Design Patent**
Shibata

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(54) **SPECIMEN ANALYZER**

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(**) Term: **14 Years**

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(30) **Foreign Application Priority Data**

Jul. 22, 2011 (JP) 2011-016853

(51) **LOC (9) Cl.** **24-01**

(52) **U.S. Cl.** **D24/216**

(58) **Field of Classification Search** D24/216,
D24/217, 219, 231, 232, 107, 169, 186; D10/81;
422/500, 547, 62-65, 67; 435/287.1, 287.3;
436/43, 45, 47

See application file for complete search history.

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(57) **CLAIM**

I claim the ornamental design for a specimen analyzer, as shown and described.

DESCRIPTION

FIG. 1 is a front view of a specimen analyzer showing my new design;

FIG. 2 is a rear view thereof;

FIG. 3 is a right side view thereof;

FIG. 4 is a top plan view thereof;

FIG. 5 is a bottom plan view thereof; and,

FIG. 6 is a perspective view thereof.

The broken lines shown represent unclaimed subject matter and form no part of the claimed design.

1 Claim, 4 Drawing Sheets

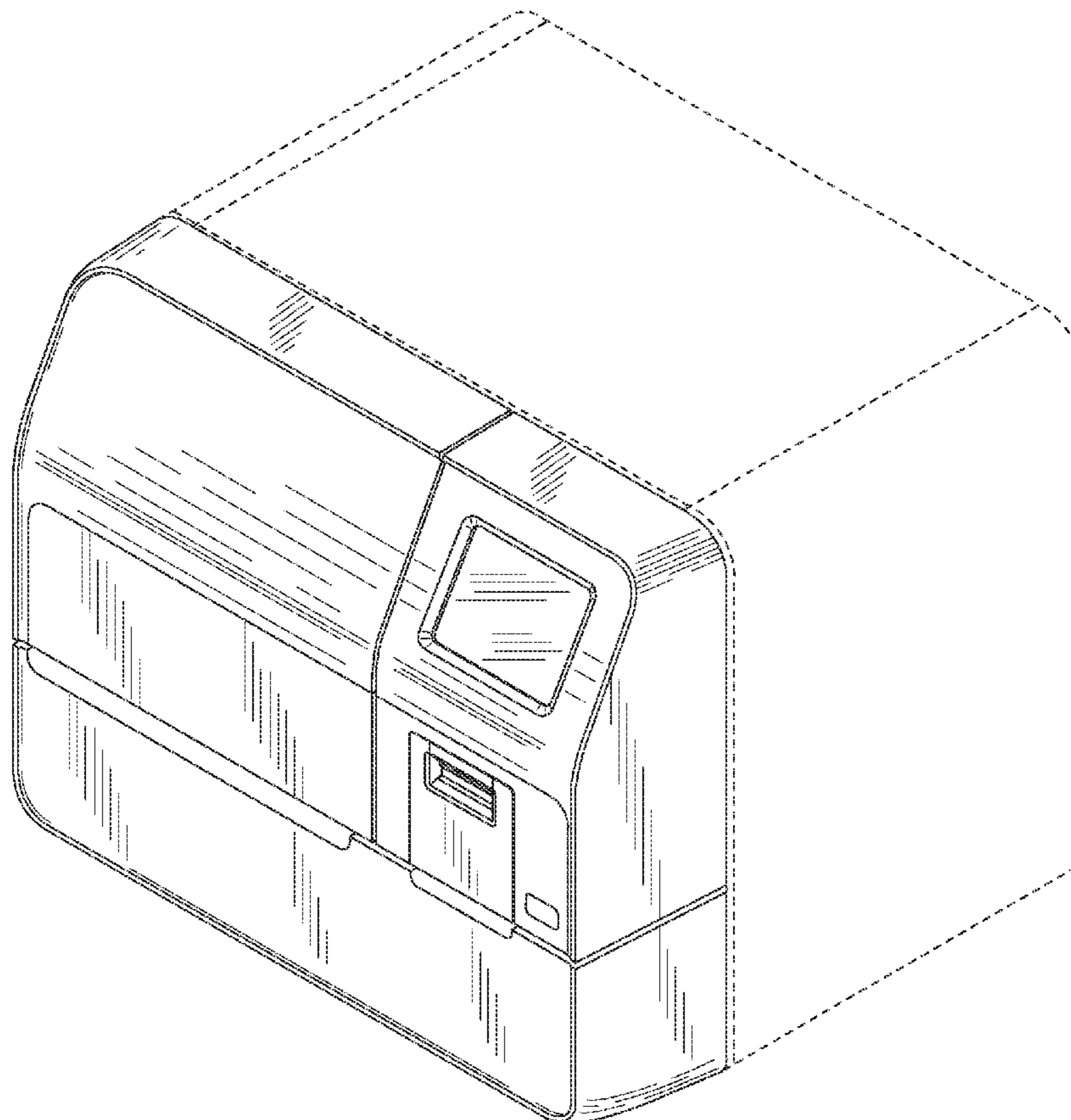


FIG.1

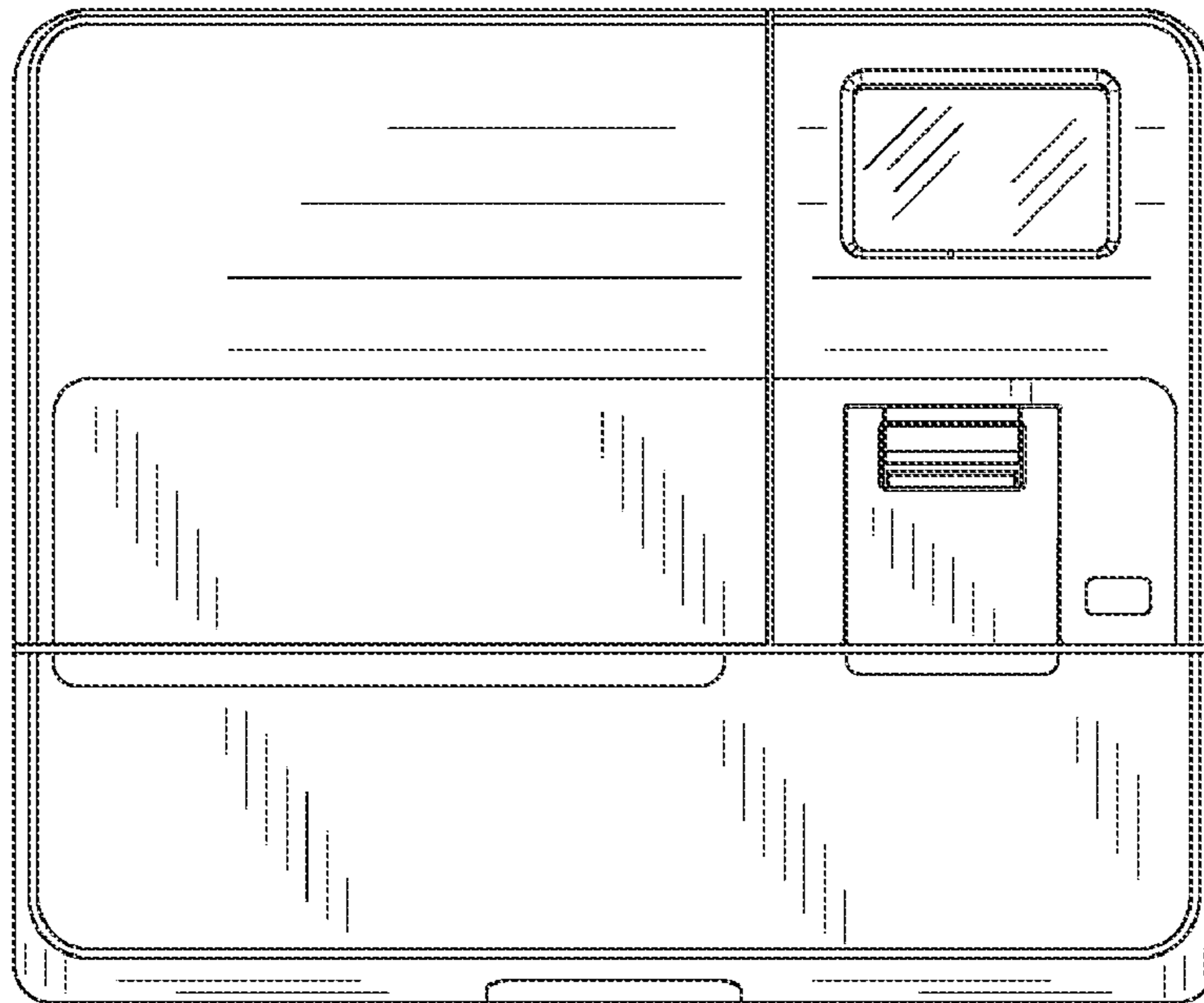


FIG.2

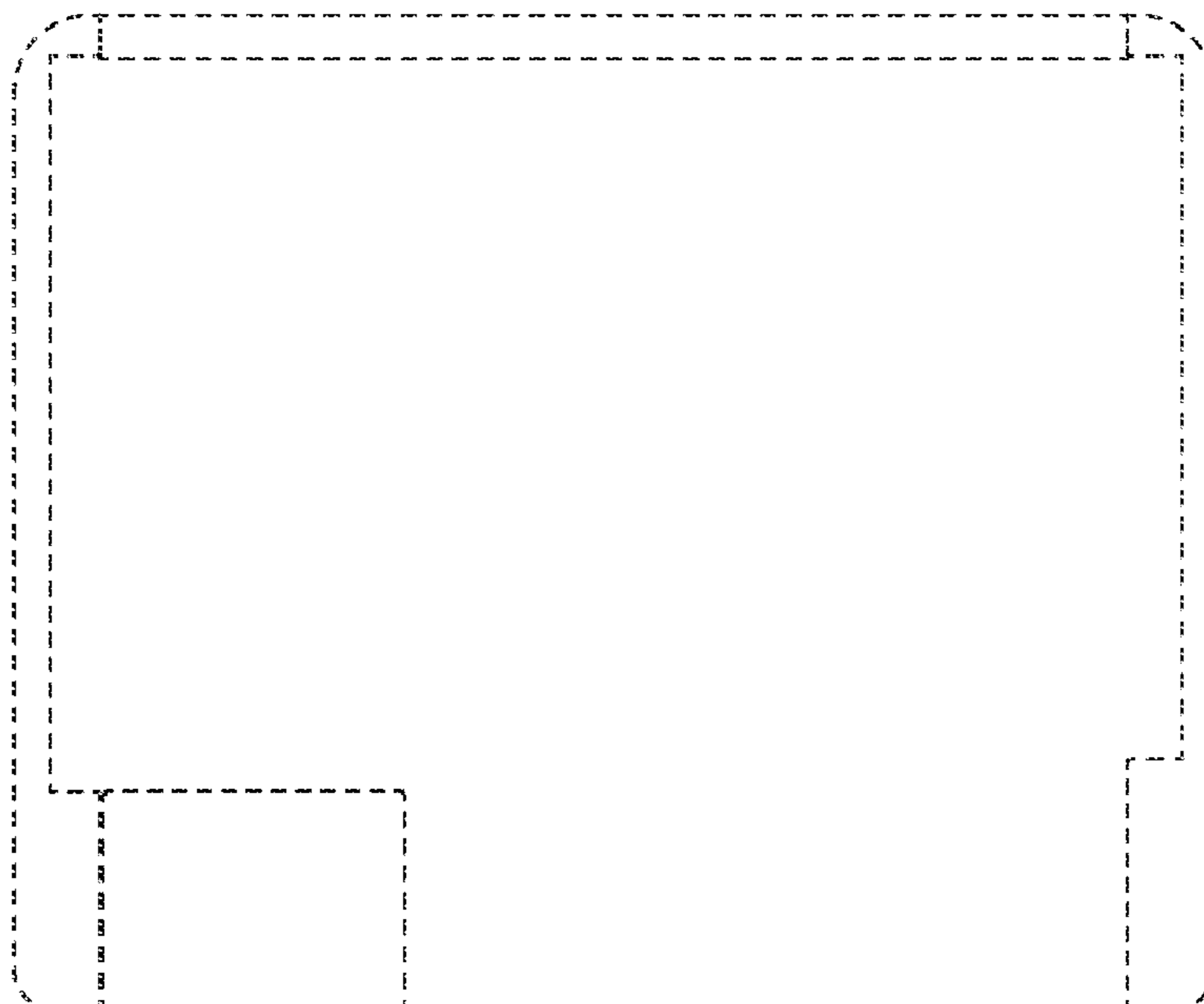


FIG.3

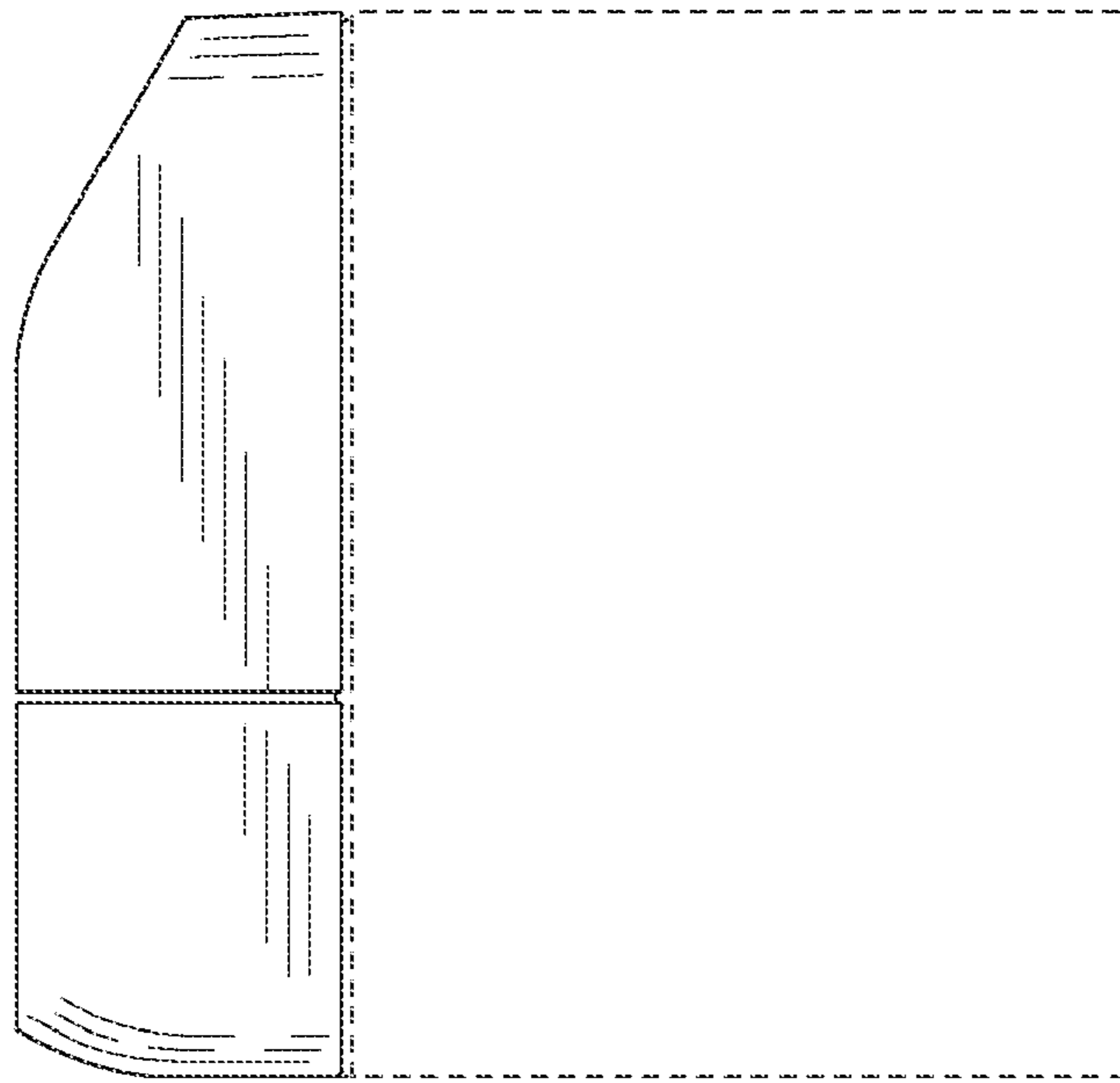


FIG.4

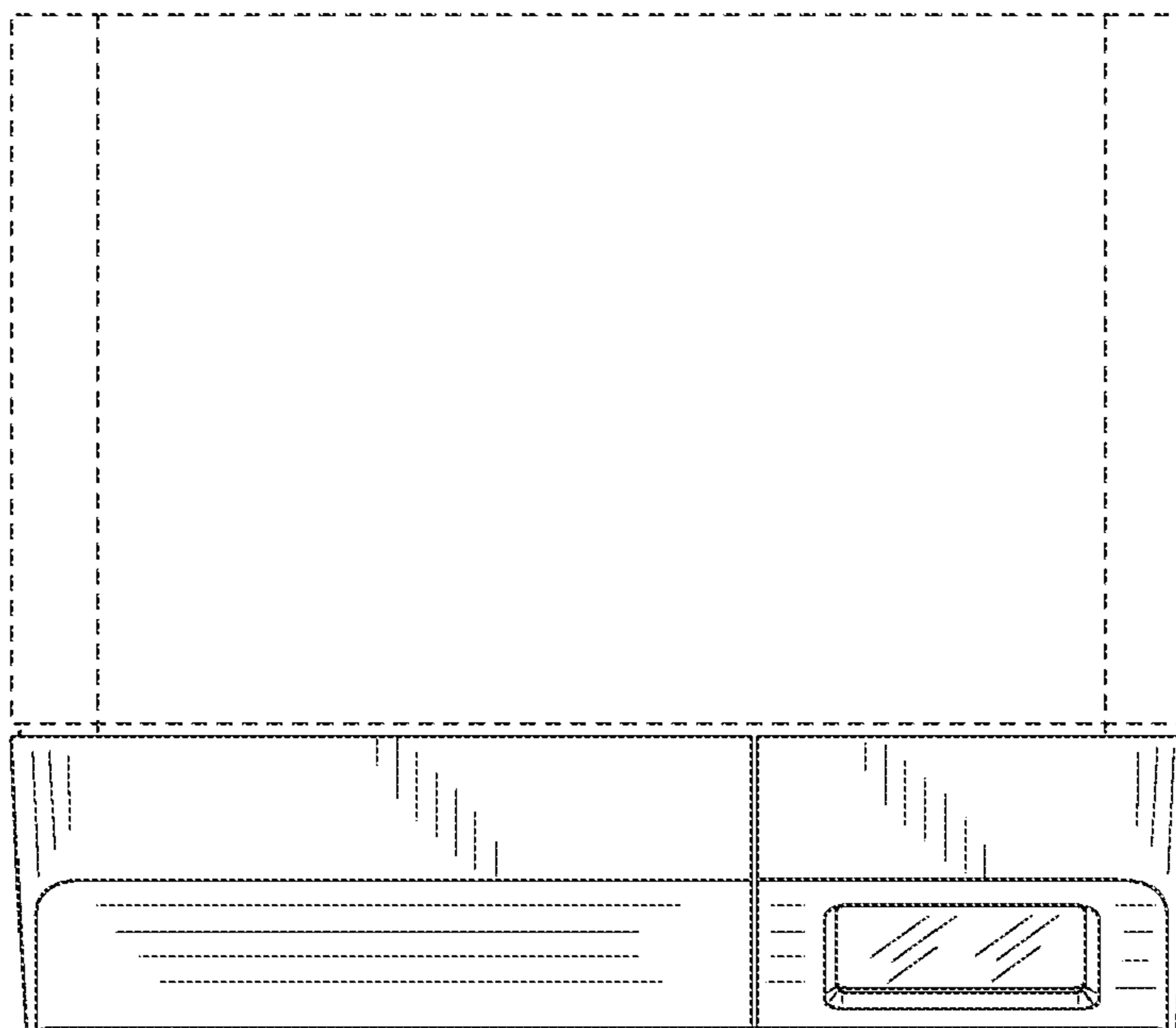


FIG.5

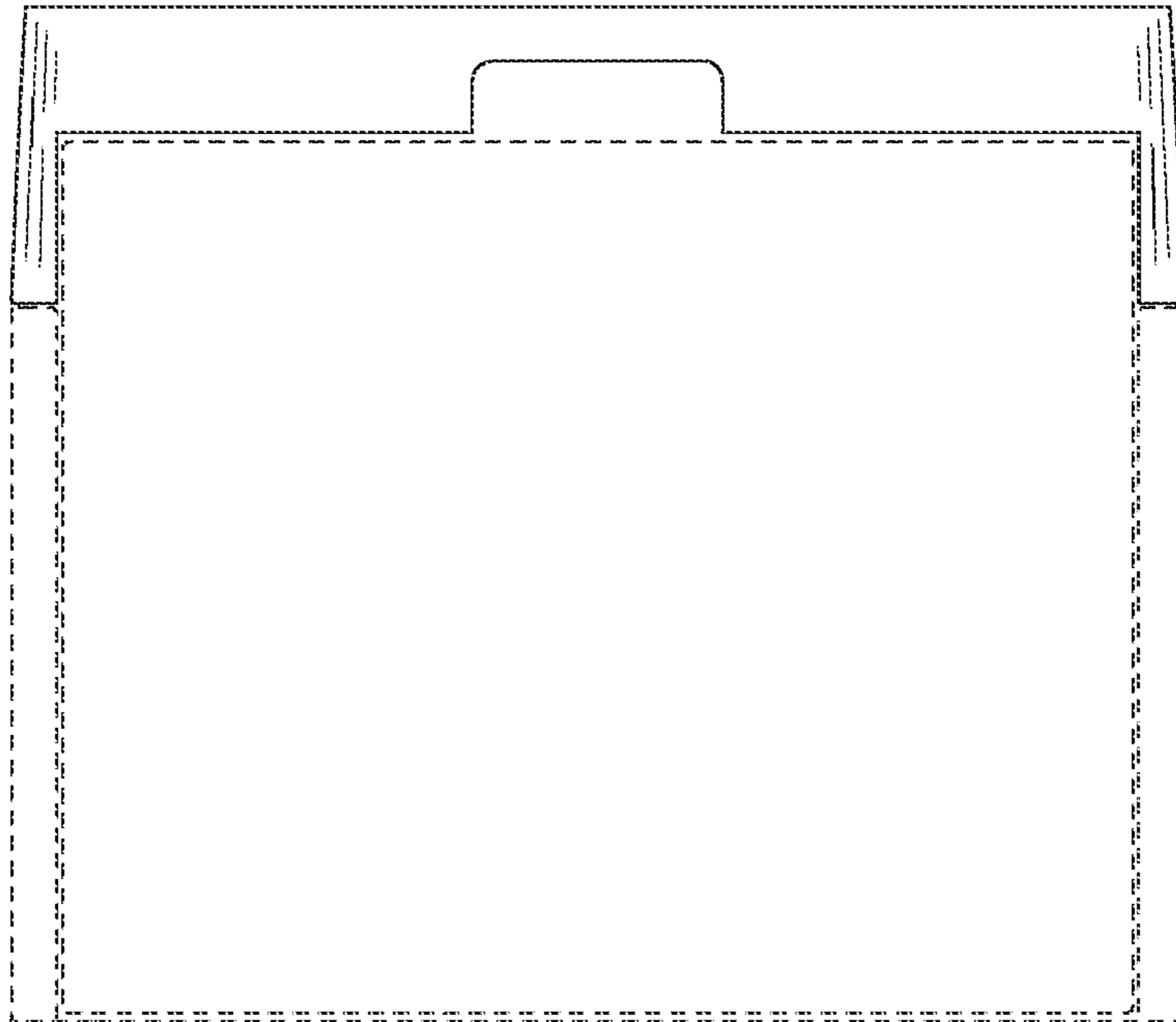


FIG.6

